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**Understanding Embedded - CPLDs (Complex Programmable Logic Devices)** 

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

## **Applications of Embedded - CPLDs**

Details	
Product Status	Obsolete
Programmable Type	In System Programmable
Delay Time tpd(1) Max	10 ns
Voltage Supply - Internal	3V ~ 3.6V
Number of Logic Elements/Blocks	4
Number of Macrocells	64
Number of Gates	1250
Number of I/O	66
Operating Temperature	0°C ~ 70°C (TA)
Mounting Type	Surface Mount
Package / Case	100-TQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/intel/epm3064atc100-10n

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

Table 2. MAX	Table 2. MAX 3000A Speed Grades								
Device			Speed Grade	1					
	-4	-5	-6	-7	-10				
EPM3032A	✓			✓	✓				
EPM3064A	✓			✓	✓				
EPM3128A		✓		✓	✓				
EPM3256A				✓	✓				
EPM3512A				✓	✓				

The MAX 3000A architecture supports 100% transistor-to-transistor logic (TTL) emulation and high–density small-scale integration (SSI), medium-scale integration (MSI), and large-scale integration (LSI) logic functions. The MAX 3000A architecture easily integrates multiple devices ranging from PALs, GALs, and 22V10s to MACH and pLSI devices. MAX 3000A devices are available in a wide range of packages, including PLCC, PQFP, and TQFP packages. See Table 3.

Table 3. MAX	3000A Max	Note (1)	)			
Device	44-Pin PLCC	44-Pin TQFP	100-Pin TQFP	144-Pin TQFP	208-Pin PQFP	256-Pin FineLine BGA
EPM3032A	34	34				
EPM3064A	34	34	66			
EPM3128A			80	96		98
EPM3256A				116	158	161
EPM3512A					172	208

#### Note:

(1) When the IEEE Std. 1149.1 (JTAG) interface is used for in–system programming or boundary–scan testing, four I/O pins become JTAG pins.

MAX 3000A devices use CMOS EEPROM cells to implement logic functions. The user–configurable MAX 3000A architecture accommodates a variety of independent combinatorial and sequential logic functions. The devices can be reprogrammed for quick and efficient iterations during design development and debugging cycles, and can be programmed and erased up to 100 times.

MAX 3000A devices contain 32 to 512 macrocells, combined into groups of 16 macrocells called logic array blocks (LABs). Each macrocell has a programmable—AND/fixed—OR array and a configurable register with independently programmable clock, clock enable, clear, and preset functions. To build complex logic functions, each macrocell can be supplemented with shareable expander and high–speed parallel expander product terms to provide up to 32 product terms per macrocell.

MAX 3000A devices provide programmable speed/power optimization. Speed-critical portions of a design can run at high speed/full power, while the remaining portions run at reduced speed/low power. This speed/power optimization feature enables the designer to configure one or more macrocells to operate at 50% or lower power while adding only a nominal timing delay. MAX 3000A devices also provide an option that reduces the slew rate of the output buffers, minimizing noise transients when non-speed-critical signals are switching. The output drivers of all MAX 3000A devices can be set for 2.5 V or 3.3 V, and all input pins are 2.5–V, 3.3–V, and 5.0-V tolerant, allowing MAX 3000A devices to be used in mixed-voltage systems.

MAX 3000A devices are supported by Altera development systems, which are integrated packages that offer schematic, text—including VHDL, Verilog HDL, and the Altera Hardware Description Language (AHDL)—and waveform design entry, compilation and logic synthesis, simulation and timing analysis, and device programming. The software provides EDIF 2 0 0 and 3 0 0, LPM, VHDL, Verilog HDL, and other interfaces for additional design entry and simulation support from other industry–standard PC– and UNIX–workstation–based EDA tools. The software runs on Windows–based PCs, as well as Sun SPARCstation, and HP 9000 Series 700/800 workstations.



For more information on development tools, see the MAX+PLUS II Programmable Logic Development System & Software Data Sheet and the Quartus Programmable Logic Development System & Software Data Sheet.

# Functional Description

The MAX 3000A architecture includes the following elements:

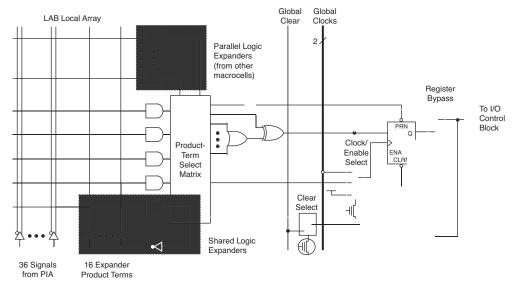
- Logic array blocks (LABs)
- Macrocells
- Expander product terms (shareable and parallel)
- Programmable interconnect array (PIA)
- I/O control blocks

The MAX 3000A architecture includes four dedicated inputs that can be used as general–purpose inputs or as high–speed, global control signals (clock, clear, and two output enable signals) for each macrocell and I/O pin. Figure 1 shows the architecture of MAX 3000A devices.

### Macrocells

MAX 3000A macrocells can be individually configured for either sequential or combinatorial logic operation. Macrocells consist of three functional blocks: logic array, product–term select matrix, and programmable register. Figure 2 shows a MAX 3000A macrocell.

Figure 2. MAX 3000A Macrocell



Combinatorial logic is implemented in the logic array, which provides five product terms per macrocell. The product–term select matrix allocates these product terms for use as either primary logic inputs (to the OR and XOR gates) to implement combinatorial functions, or as secondary inputs to the macrocell's register preset, clock, and clock enable control functions.

Two kinds of expander product terms ("expanders") are available to supplement macrocell logic resources:

- Shareable expanders, which are inverted product terms that are fed back into the logic array
- Parallel expanders, which are product terms borrowed from adjacent macrocells

The Altera development system automatically optimizes product–term allocation according to the logic requirements of the design.

For registered functions, each macrocell flipflop can be individually programmed to implement D, T, JK, or SR operation with programmable clock control. The flipflop can be bypassed for combinatorial operation. During design entry, the designer specifies the desired flipflop type; the Altera development system software then selects the most efficient flipflop operation for each registered function to optimize resource utilization.

Each programmable register can be clocked in three different modes:

- Global clock signal mode, which achieves the fastest clock–to–output performance.
- Global clock signal enabled by an active—high clock enable. A clock enable is generated by a product term. This mode provides an enable on each flipflop while still achieving the fast clock—to—output performance of the global clock.
- Array clock implemented with a product term. In this mode, the flipflop can be clocked by signals from buried macrocells or I/O pins.

Two global clock signals are available in MAX 3000A devices. As shown in Figure 1, these global clock signals can be the true or the complement of either of the two global clock pins, GCLK1 or GCLK2.

Each register also supports asynchronous preset and clear functions. As shown in Figure 2, the product–term select matrix allocates product terms to control these operations. Although the product–term–driven preset and clear from the register are active high, active–low control can be obtained by inverting the signal within the logic array. In addition, each register clear function can be individually driven by the active–low dedicated global clear pin (GCLRn).

All registers are cleared upon power-up. By default, all registered outputs drive low when the device is powered up. You can set the registered outputs to drive high upon power-up through the Quartus<sup>®</sup> II software. Quartus II software uses the NOT Gate Push-Back method, which uses an additional macrocell to set the output high. To set this in the Quartus II software, go to the Assignment Editor and set the **Power-Up Level** assignment for the register to **High**.

## **Expander Product Terms**

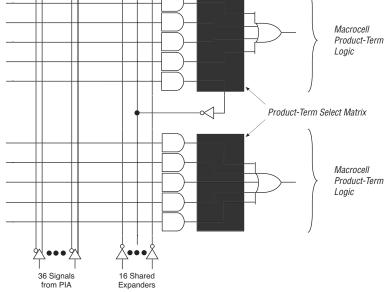
Although most logic functions can be implemented with the five product terms available in each macrocell, highly complex logic functions require additional product terms. Another macrocell can be used to supply the required logic resources. However, the MAX 3000A architecture also offers both shareable and parallel expander product terms ("expanders") that provide additional product terms directly to any macrocell in the same LAB. These expanders help ensure that logic is synthesized with the fewest possible logic resources to obtain the fastest possible speed.

## Shareable Expanders

Each LAB has 16 shareable expanders that can be viewed as a pool of uncommitted single product terms (one from each macrocell) with inverted outputs that feed back into the logic array. Each shareable expander can be used and shared by any or all macrocells in the LAB to build complex logic functions. Shareable expanders incur a small delay  $(t_{SFXP})$ . Figure 3 shows how shareable expanders can feed multiple macrocells.

Figure 3. MAX 3000A Shareable Expanders

Shareable expanders can be shared by any or all macrocells in an LAB.



### Parallel Expanders

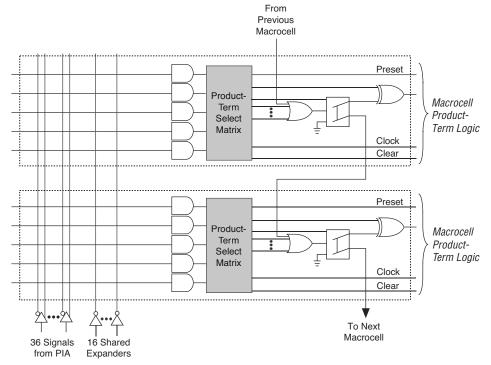
Parallel expanders are unused product terms that can be allocated to a neighboring macrocell to implement fast, complex logic functions. Parallel expanders allow up to 20 product terms to directly feed the macrocell OR logic, with five product terms provided by the macrocell and 15 parallel expanders provided by neighboring macrocells in the LAB.

The Altera development system compiler can automatically allocate up to three sets of up to five parallel expanders to the macrocells that require additional product terms. Each set of five parallel expanders incurs a small, incremental timing delay ( $t_{PEXP}$ ). For example, if a macrocell requires 14 product terms, the compiler uses the five dedicated product terms within the macrocell and allocates two sets of parallel expanders; the first set includes five product terms, and the second set includes four product terms, increasing the total delay by  $2 \times t_{PEXP}$ .

Two groups of eight macrocells within each LAB (e.g., macrocells 1 through 8 and 9 through 16) form two chains to lend or borrow parallel expanders. A macrocell borrows parallel expanders from lower–numbered macrocells. For example, macrocell 8 can borrow parallel expanders from macrocell 7, from macrocells 7 and 6, or from macrocells 7, 6, and 5. Within each group of eight, the lowest–numbered macrocell can only lend parallel expanders and the highest–numbered macrocell can only borrow them. Figure 4 shows how parallel expanders can be borrowed from a neighboring macrocell.

Figure 4. MAX 3000A Parallel Expanders

Unused product terms in a macrocell can be allocated to a neighboring macrocell.



## **Programmable Interconnect Array**

Logic is routed between LABs on the PIA. This global bus is a programmable path that connects any signal source to any destination on the device. All MAX 3000A dedicated inputs, I/O pins, and macrocell outputs feed the PIA, which makes the signals available throughout the entire device. Only the signals required by each LAB are actually routed from the PIA into the LAB. Figure 5 shows how the PIA signals are routed into the LAB. An EEPROM cell controls one input to a two-input AND gate, which selects a PIA signal to drive into the LAB.

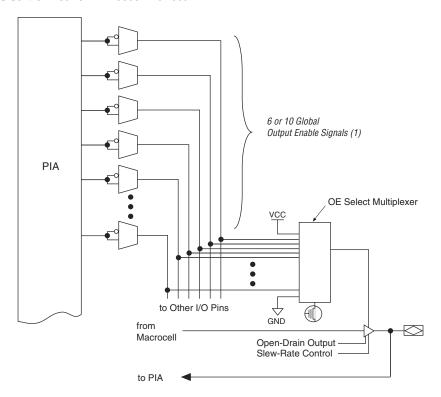


Figure 6. I/O Control Block of MAX 3000A Devices

### Note:

(1) EPM3032A, EPM3064A, EPM3128A, and EPM3256A devices have six output enables. EPM3512A devices have 10 output enables.

When the tri–state buffer control is connected to ground, the output is tri-stated (high impedance), and the  $\rm I/O$  pin can be used as a dedicated input. When the tri–state buffer control is connected to  $\rm V_{CC}$ , the output is enabled.

The MAX 3000A architecture provides dual I/O feedback, in which macrocell and pin feedbacks are independent. When an I/O pin is configured as an input, the associated macrocell can be used for buried logic.

The programming times described in Tables 4 through 6 are associated with the worst-case method using the enhanced ISP algorithm.

Table 4. MAX 3000A t <sub>PULSE</sub> & Cycle <sub>TCK</sub> Values										
Device	Progra	Programming Stand-Alone Verificati								
	t <sub>PPULSE</sub> (s)	Cycle <sub>PTCK</sub>	t <sub>VPULSE</sub> (s)	Cycle <sub>VTCK</sub>						
EPM3032A	2.00	55,000	0.002	18,000						
EPM3064A	2.00	105,000	0.002	35,000						
EPM3128A	2.00	205,000	0.002	68,000						
EPM3256A	2.00	447,000	0.002	149,000						
EPM3512A	2.00	890,000	0.002	297,000						

Tables 5 and 6 show the in-system programming and stand alone verification times for several common test clock frequencies.

Table 5. MAX 3000A In-System Programming Times for Different Test Clock Frequencies										
Device				1	TCK				Units	
	10 MHz	5 MHz	2 MHz	1 MHz	500 kHz	200 kHz	100 kHz	50 kHz		
EPM3032A	2.01	2.01	2.03	2.06	2.11	2.28	2.55	3.10	S	
EPM3064A	2.01	2.02	2.05	2.11	2.21	2.53	3.05	4.10	S	
EPM3128A	2.02	2.04	2.10	2.21	2.41	3.03	4.05	6.10	S	
EPM3256A	2.05	2.09	2.23	2.45	2.90	4.24	6.47	10.94	S	
EPM3512A	2.09	2.18	2.45	2.89	3.78	6.45	10.90	19.80	s	

Table 6. MAX 3000A Stand-Alone Verification Times for Different Test Clock Frequencies										
Device				1	TCK				Units	
	10 MHz	5 MHz	2 MHz	1 MHz	500 kHz	200 kHz	100 kHz	50 kHz		
EPM3032A	0.00	0.01	0.01	0.02	0.04	0.09	0.18	0.36	S	
EPM3064A	0.01	0.01	0.02	0.04	0.07	0.18	0.35	0.70	S	
EPM3128A	0.01	0.02	0.04	0.07	0.14	0.34	0.68	1.36	S	
EPM3256A	0.02	0.03	0.08	0.15	0.30	0.75	1.49	2.98	S	
EPM3512A	0.03	0.06	0.15	0.30	0.60	1.49	2.97	5.94	S	

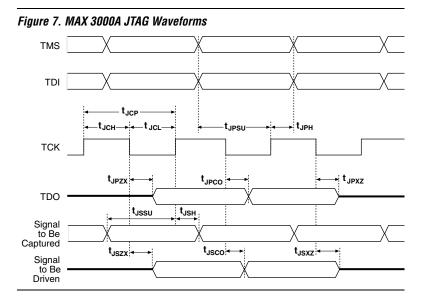


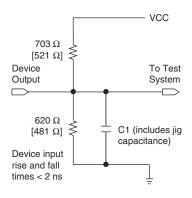
Figure 7 shows the timing information for the JTAG signals.

Table 10 shows the JTAG timing parameters and values for MAX 3000A devices.

Table 1	O. JTAG Timing Parameters & Values for MAX 30	00A De	vices	
Symbol	Parameter	Min	Max	Unit
t <sub>JCP</sub>	TCK clock period	100		ns
t <sub>JCH</sub>	TCK clock high time	50		ns
t <sub>JCL</sub>	TCK clock low time	50		ns
t <sub>JPSU</sub>	JTAG port setup time	20		ns
t <sub>JPH</sub>	JTAG port hold time	45		ns
t <sub>JPCO</sub>	JTAG port clock to output		25	ns
t <sub>JPZX</sub>	JTAG port high impedance to valid output		25	ns
t <sub>JPXZ</sub>	JTAG port valid output to high impedance		25	ns
t <sub>JSSU</sub>	Capture register setup time	20		ns
t <sub>JSH</sub>	Capture register hold time	45		ns
t <sub>JSCO</sub>	Update register clock to output		25	ns
t <sub>JSZX</sub>	Update register high impedance to valid output		25	ns
t <sub>JSXZ</sub>	Update register valid output to high impedance		25	ns

## Figure 8. MAX 3000A AC Test Conditions

Power supply transients can affect AC measurements. Simultaneous transitions of multiple outputs should be avoided for accurate measurement. Threshold tests must not be performed under AC conditions. Large-amplitude, fastground-current transients normally occur as the device outputs discharge the load capacitances. When these transients flow through the parasitic inductance between the device ground pin and the test system ground, significant reductions in observable noise immunity can result. Numbers in brackets are for 2.5-V outputs. Numbers without brackets are for 3.3-V devices or outputs.



## Operating Conditions

Tables 12 through 15 provide information on absolute maximum ratings, recommended operating conditions, DC operating conditions, and capacitance for MAX 3000A devices.

Table 1	Table 12. MAX 3000A Device Absolute Maximum Ratings Note (1)											
Symbol	Parameter	Min	Max	Unit								
V <sub>CC</sub>	Supply voltage	With respect to ground (2)	-0.5	4.6	V							
VI	DC input voltage	1	-2.0	5.75	V							
I <sub>OUT</sub>	DC output current, per pin		-25	25	mA							
T <sub>STG</sub>	Storage temperature	No bias	-65	150	° C							
$T_A$	Ambient temperature	Under bias	-65	135	° C							
$T_{J}$	Junction temperature	PQFP and TQFP packages, under bias		135	° C							

 $V_{CCINT} = 3.3 V$ 

V<sub>CCIO</sub> = 2.5 V

Temperature = 25 °C

150  $I_{OL}$ 100 Typical I<sub>O</sub>  $V_{CCINT} = 3.3 V$ Output  $V_{CCIO} = 3.3 V$ Current (mA) Temperature = 25 °C 50  $I_{OH}$ 2 V<sub>O</sub> Output Voltage (V) 2.5 V 150  $I_{OL}$ 

Figure 9. Output Drive Characteristics of MAX 3000A Devices

3.3 V

## Power Sequencing & Hot-Socketing

Because MAX 3000A devices can be used in a mixed–voltage environment, they have been designed specifically to tolerate any possible power–up sequence. The  $\rm V_{CCIO}$  and  $\rm V_{CCINT}$  power planes can be powered in any order.

V<sub>O</sub> Output Voltage (V)

Signals can be driven into MAX 3000A devices before and during power-up without damaging the device. In addition, MAX 3000A devices do not drive out during power-up. Once operating conditions are reached, MAX 3000A devices operate as specified by the user.

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100

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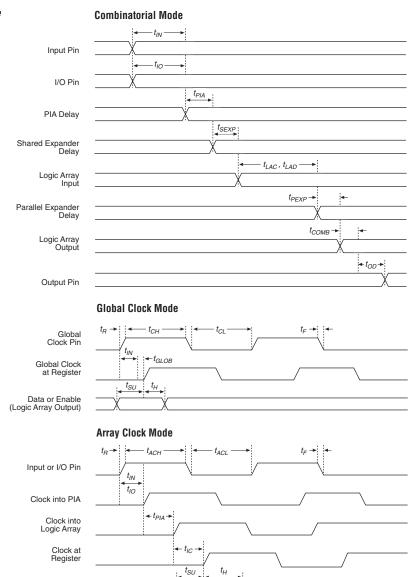
Typical I<sub>O</sub>

Current (mA)

Output

## Figure 11. MAX 3000A Switching Waveforms

 $t_R$  &  $t_F$  < 2 ns. Inputs are driven at 3 V for a logic high and 0 V for a logic low. All timing characteristics are measured at 1.5 V.



 $-t_{PIA}$ 

 $\leftarrow t_{OD} \rightarrow$ 

 $\leftarrow t_{CLR}, t_{PRE} \rightarrow$ 

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 $t_{RD}$ 

 $\leftarrow t_{PIA} \rightarrow$ 

**←** t<sub>OD</sub>

Data from Logic Array

Register to PIA to Logic Array

Register Output to Pin

Tables 16 through 23 show EPM3032A, EPM3064A, EPM3128A, EPM3256A, and EPM3512A timing information.

	6. EPM3032A External 1	, 		Note (1)		•			T	
Symbol	Parameter	Conditions			Speed	Grade	1		Unit	
			-4		<b>-7</b>		-10			
			Min	Max	Min	Max	Min	Max		
t <sub>PD1</sub>	Input to non- registered output	C1 = 35 pF (2)		4.5		7.5		10	ns	
t <sub>PD2</sub>	I/O input to non– registered output	C1 = 35 pF (2)		4.5		7.5		10	ns	
t <sub>SU</sub>	Global clock setup time	(2)	2.9		4.7		6.3		ns	
t <sub>H</sub>	Global clock hold time	(2)	0.0		0.0		0.0		ns	
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF	1.0	3.0	1.0	5.0	1.0	6.7	ns	
t <sub>CH</sub>	Global clock high time		2.0		3.0		4.0		ns	
t <sub>CL</sub>	Global clock low time		2.0		3.0		4.0		ns	
t <sub>ASU</sub>	Array clock setup time	(2)	1.6		2.5		3.6		ns	
t <sub>AH</sub>	Array clock hold time	(2)	0.3		0.5		0.5		ns	
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF (2)	1.0	4.3	1.0	7.2	1.0	9.4	ns	
t <sub>ACH</sub>	Array clock high time		2.0		3.0		4.0		ns	
t <sub>ACL</sub>	Array clock low time		2.0		3.0		4.0		ns	
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(3)	2.0		3.0		4.0		ns	
t <sub>CNT</sub>	Minimum global clock period	(2)		4.4		7.2		9.7	ns	
f <sub>CNT</sub>	Maximum internal global clock frequency	(2), (4)	227.3		138.9		103.1		MHz	
t <sub>ACNT</sub>	Minimum array clock period	(2)		4.4		7.2		9.7	ns	
f <sub>ACNT</sub>	Maximum internal array clock frequency	(2), (4)	227.3		138.9		103.1		MHz	

Table 17	Table 17. EPM3032A Internal Timing Parameters (Part 2 of 2) Note (1)									
Symbol	Parameter	Conditions		Speed Grade						
			_	4	-7			-10		
			Min	Max	Min	Max	Min	Max		
t <sub>PIA</sub>	PIA delay	(2)		0.9		1.5		2.1	ns	
$t_{LPA}$	Low-power adder	(5)		2.5		4.0		5.0	ns	

Table 18	3. EPM3064A External Timin	g Parameters	Note (	1)					
Symbol	Parameter	Conditions	Speed Grade						
			-4		-7		-10		
			Min	Max	Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non–registered output	C1 = 35 pF (2)		4.5		7.5		10.0	ns
t <sub>PD2</sub>	I/O input to non–registered output	C1 = 35 pF <i>(2)</i>		4.5		7.5		10.0	ns
t <sub>SU</sub>	Global clock setup time	(2)	2.8		4.7		6.2		ns
t <sub>H</sub>	Global clock hold time	(2)	0.0		0.0		0.0		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF	1.0	3.1	1.0	5.1	1.0	7.0	ns
t <sub>CH</sub>	Global clock high time		2.0		3.0		4.0		ns
t <sub>CL</sub>	Global clock low time		2.0		3.0		4.0		ns
t <sub>ASU</sub>	Array clock setup time	(2)	1.6		2.6		3.6		ns
t <sub>AH</sub>	Array clock hold time	(2)	0.3		0.4		0.6		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF (2)	1.0	4.3	1.0	7.2	1.0	9.6	ns
t <sub>ACH</sub>	Array clock high time		2.0		3.0		4.0		ns
t <sub>ACL</sub>	Array clock low time		2.0		3.0		4.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(3)	2.0		3.0		4.0		ns
t <sub>CNT</sub>	Minimum global clock period	(2)		4.5		7.4		10.0	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(2), (4)	222.2		135.1		100.0		MHz
t <sub>ACNT</sub>	Minimum array clock period	(2)		4.5		7.4		10.0	ns
f <sub>ACNT</sub>	Maximum internal array clock frequency	(2), (4)	222.2		135.1		100.0		MHz

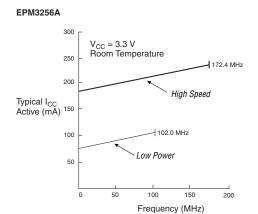
Table 19	Table 19. EPM3064A Internal Timing Parameters (Part 2 of 2) Note (1)										
Symbol	Parameter	Conditions		Speed Grade							
			_	4	-7		-10				
			Min	Max	Min	Max	Min	Max			
t <sub>CLR</sub>	Register clear time			1.3		2.1		2.9	ns		
t <sub>PIA</sub>	PIA delay	(2)		1.0		1.7		2.3	ns		
$t_{LPA}$	Low-power adder	(5)		3.5		4.0		5.0	ns		

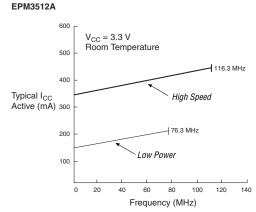
Table 20. EPM3128A External Timing Parameters Note (1)									
Symbol	Parameter	Conditions	Speed Grade						
			-5		-7		-10		=
			Min	Max	Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non– registered output	C1 = 35 pF (2)		5.0		7.5		10	ns
t <sub>PD2</sub>	I/O input to non– registered output	C1 = 35 pF (2)		5.0		7.5		10	ns
t <sub>SU</sub>	Global clock setup time	(2)	3.3		4.9		6.6		ns
t <sub>H</sub>	Global clock hold time	(2)	0.0		0.0		0.0		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF	1.0	3.4	1.0	5.0	1.0	6.6	ns
t <sub>CH</sub>	Global clock high time		2.0		3.0		4.0		ns
t <sub>CL</sub>	Global clock low time		2.0		3.0		4.0		ns
t <sub>ASU</sub>	Array clock setup time	(2)	1.8		2.8		3.8		ns
t <sub>AH</sub>	Array clock hold time	(2)	0.2		0.3		0.4		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF (2)	1.0	4.9	1.0	7.1	1.0	9.4	ns
t <sub>ACH</sub>	Array clock high time		2.0		3.0		4.0		ns
t <sub>ACL</sub>	Array clock low time		2.0		3.0		4.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(3)	2.0		3.0		4.0		ns
t <sub>CNT</sub>	Minimum global clock period	(2)		5.2		7.7		10.2	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(2), (4)	192.3		129.9		98.0		MHz
t <sub>ACNT</sub>	Minimum array clock period	(2)		5.2		7.7		10.2	ns

Symbol	Parameter	Conditions	Speed Grade					
			_	7	-10			
			Min	Max	Min	Max		
t <sub>CNT</sub>	Minimum global clock period	(2)		7.9		10.5	ns	
f <sub>CNT</sub>	Maximum internal global clock frequency	(2), (4)	126.6		95.2		MHz	
t <sub>ACNT</sub>	Minimum array clock period	(2)		7.9		10.5	ns	
f <sub>ACNT</sub>	Maximum internal array clock frequency	(2), (4)	126.6		95.2		MHz	

Symbol	Parameter	Conditions		Unit			
			-7		-10		
			Min	Max	Min	Max	
t <sub>IN</sub>	Input pad and buffer delay			0.9		1.2	ns
t <sub>IO</sub>	I/O input pad and buffer delay			0.9		1.2	ns
t <sub>SEXP</sub>	Shared expander delay			2.8		3.7	ns
t <sub>PEXP</sub>	Parallel expander delay			0.5		0.6	ns
$t_{LAD}$	Logic array delay			2.2		2.8	ns
$t_{LAC}$	Logic control array delay			1.0		1.3	ns
t <sub>IOE</sub>	Internal output enable delay			0.0		0.0	ns
t <sub>OD1</sub>	Output buffer and pad delay, slow slew rate = off V <sub>CCIO</sub> = 3.3 V	C1 = 35 pF		1.2		1.6	ns
t <sub>OD2</sub>	Output buffer and pad delay, slow slew rate = off V <sub>CCIO</sub> = 2.5 V	C1 = 35 pF		1.7		2.1	ns
t <sub>OD3</sub>	Output buffer and pad delay, slow slew rate = on V <sub>CCIO</sub> = 2.5 V or 3.3 V	C1 = 35 pF		6.2		6.6	ns
t <sub>ZX1</sub>	Output buffer enable delay, slow slew rate = off V <sub>CCIO</sub> = 3.3 V	C1 = 35 pF		4.0		5.0	ns
t <sub>ZX2</sub>	Output buffer enable delay, slow slew rate = off V <sub>CCIO</sub> = 2.5 V	C1 = 35 pF		4.5		5.5	ns

Figure 13.  $I_{CC}$  vs. Frequency for MAX 3000A Devices





## Device Pin-Outs

See the Altera web site (http://www.altera.com) or the *Altera Digital Library* for pin–out information.

Figures 14 through 18 show the package pin-out diagrams for MAX 3000A devices.

Figure 14. 44-Pin PLCC/TQFP Package Pin-Out Diagram

Package outlines not drawn to scale.

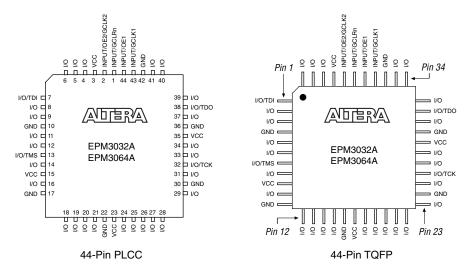


Figure 17. 208-Pin PQFP Package Pin-Out Diagram

Package outline not drawn to scale.

